



FIG. 1

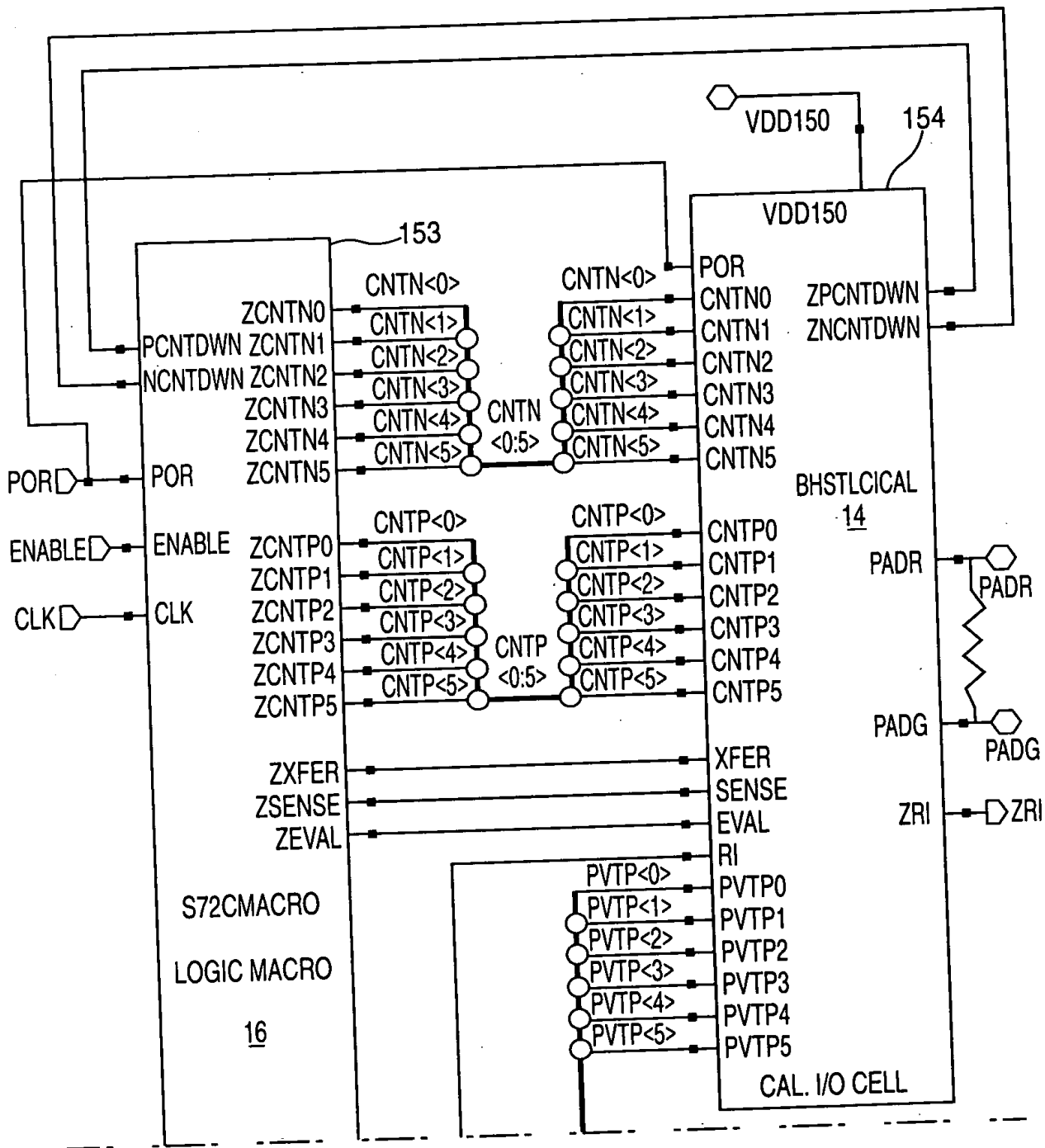


FIG. 2A

2-A
2-B

FIG. 2

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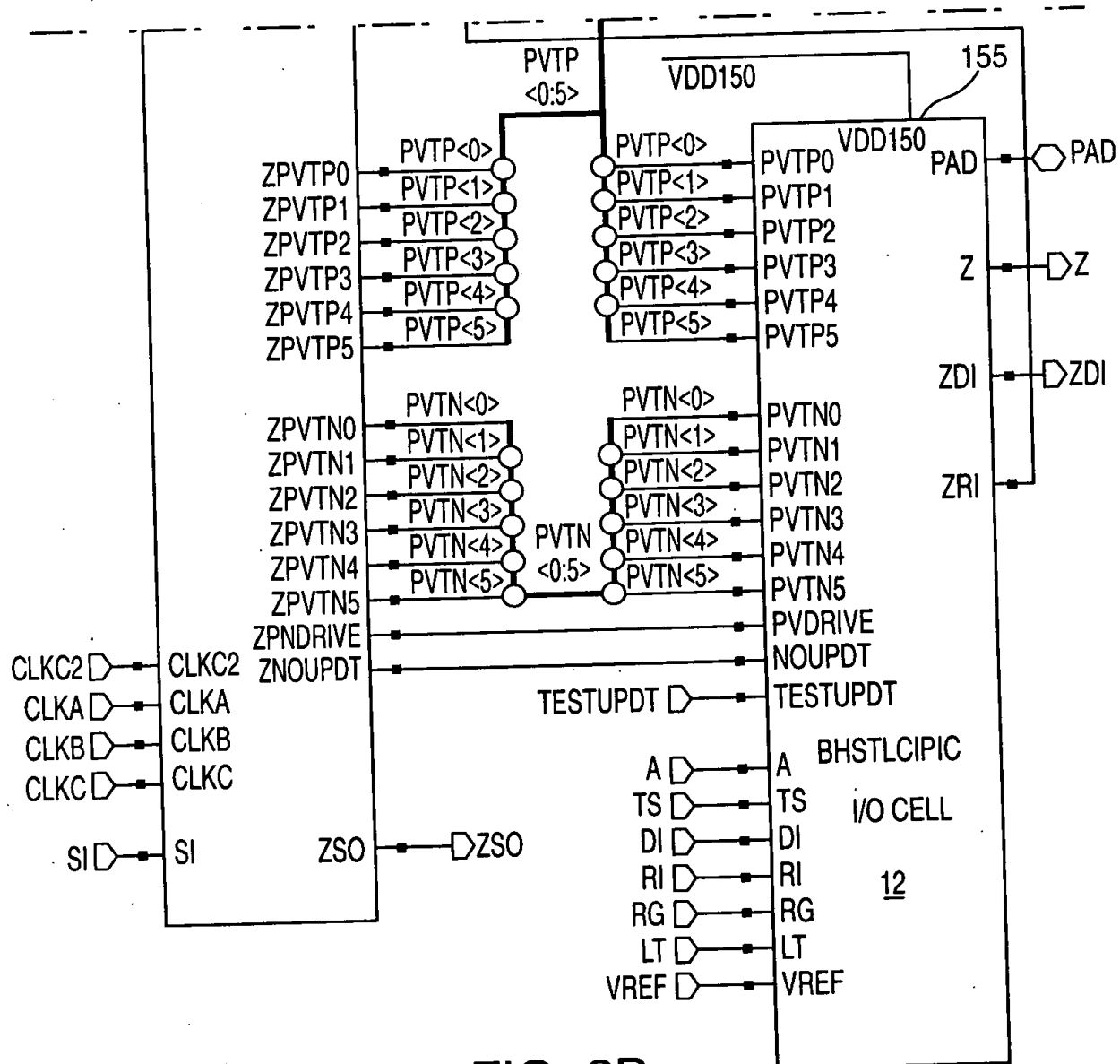
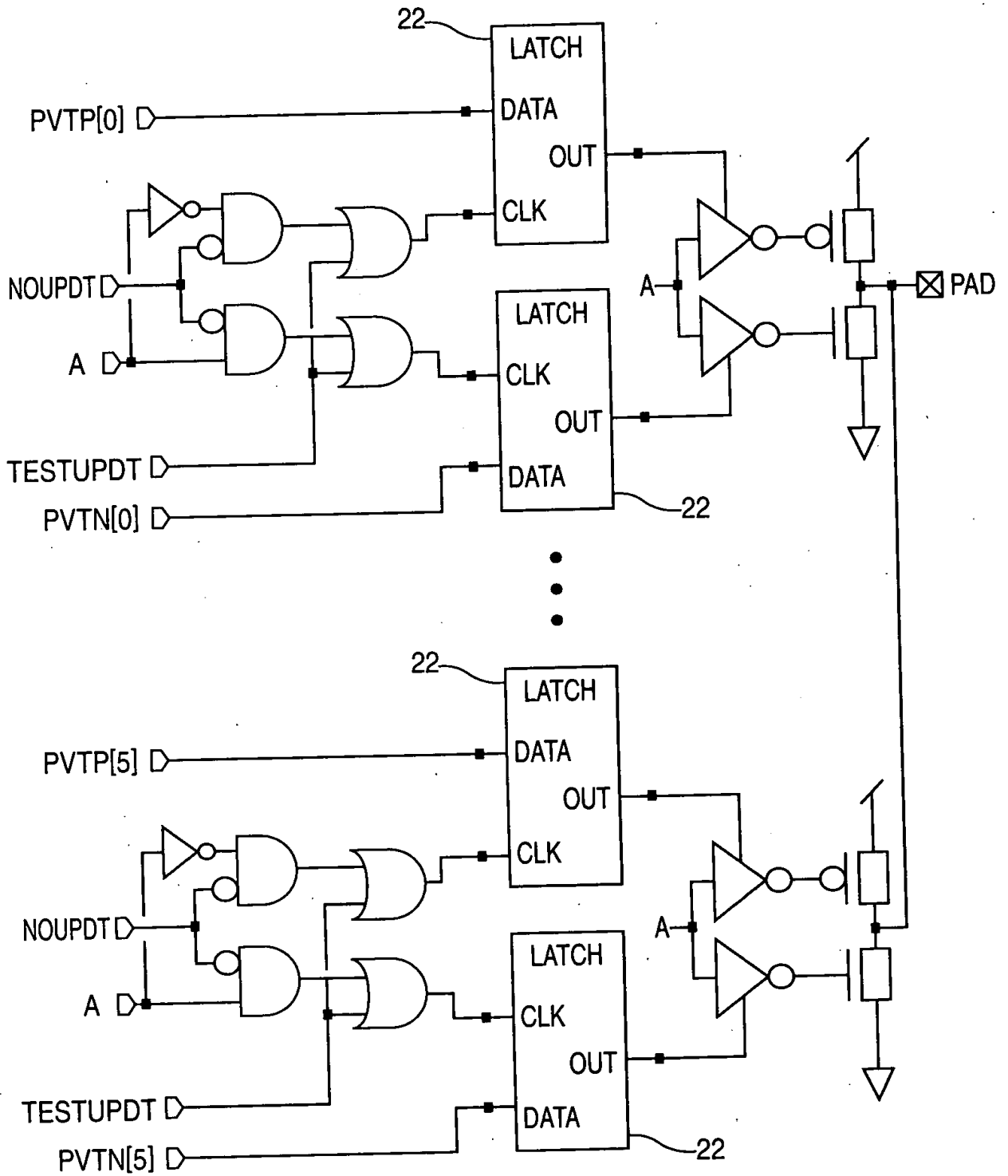


FIG. 2B

FIG. 3.



DRIVER-IMPEDANCE UPDATE LOGIC
FIG. 4

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INPUTS			OUTPUTS		
A	NOUPDT	TESTUPDT	P-BITS	N-BITS	COMMENTS
X	1	0	NC ¹	NC ¹	INPUT BITS CHANGING
0	0	0	UPDATE ²	HOLD ²	UPDATE P-BITS ONLY
1	0	0	HOLD ³	UPDATE ³	UPDATE N-BITS ONLY
X	X	1	UPDATE ⁴	UPDATE ⁴	FORCE UPDATE TO ALL P/N-BITS

1. WHEN "NOUPDT" IS HIGH, THE INPUT CONTROL BITS WILL BE UPDATED AND THE I/O WILL HOLD THE PRESENT STATE OF THE CONTROL BITS UNTIL "NOUPDT" GOES LOW. THIS PREVENTS THE I/O FROM CHANGING THE OUTPUT IMPEDANCE WHILE THE INPUT CONTROL BITS ARE UNSTABLE.
2. WHEN THE DATA INPUT "A" CHANGES FROM A HIGH TO A LOW STATE, THE PULL-UP IMPEDANCE WILL BE UPDATED. THE P-BITS WILL BE LATCHED WHEN "A" TOGGLES FROM LOW TO HIGH.
3. WHEN THE DATA INPUT "A" CHANGES FROM A LOW TO A HIGH STATE, THE PULL-DOWN IMPEDANCE WILL BE UPDATED. THE N-BITS WILL BE LATCHED WHEN "A" TOGGLES FROM HIGH TO LOW.
4. WHEN "TESTUPDT" IS HIGH, ALL THE DATA LATCHES WILL BECOME TRANSPARENT AND BOTH THE PULL-UP AND PULL-DOWN IMPEDANCE WILL BE UPDATED.

NOTE: "TESTUPDT" IS USEFUL TO THE USER TO UPDATE THE OUTPUT IMPEDANCE IF THE I/O HAS BEEN SITTING IN HI-Z OR THE "A" INPUT HAS NOT TOGGLED FOR A LONG PERIOD OF TIME.

DRIVER IMPEDANCE UPDATE TABLE

FIG. 5

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INPUTS					OUTPUTS	
A	TS	DI	PNDRIIVE	PVTN[0:5] PVTP[0:5]	PAD	ZDI
-	0	-	-	-	Hi-Z ¹	D1
-	-	0	-	-	Hi-Z ¹	D1
-	1	1	0	0	Hi-Z ²	D1
-	1	1	-	1 ³	A	D1
-	1	1	1	-	A	D1

- PAD IS Hi-Z IF DRIVER IS NOT EXTERNALLY TERMINATED. PAD IS AT " $V_{dd}/2$ " IF DRIVER IS TERMINATED (OFF-CHIP).
- PNDRIIVE=0 IS FOR TEST ONLY. THIS FORCES THE DEFAULT BIT OFF SUCH THAT THE LSB'S CAN BE TESTED.
- AT LEAST ONE PVTN BIT AND ONE PVTP BIT MUST BE AT A LOGIC "1".

NOTES: A. LOGICAL "1" = $V_{ddq} = V_{DD150} = 1.5V$. (NOMINAL)

B. NEW DELAY RULE (NDR) WILL BE BASED ON DRIVER TERMINATED OFF-CHIP.

DRIVER TRUTH TABLE

FIG. 6

INPUTS					OUTPUTS		
PAD	LT	RI	RG	VREF	Z	ZRI	COMMENTS
-	-	-	0	-	0	RI	TEST MODE
-	-	0	-	-	0	RI	TEST MODE
1 ¹	0	1	1	-	1	RI	FUNCTIONAL MODE
0 ²	0	1	1	-	0	RI	FUNCTIONAL MODE
1 ³	1	1	1	-	1	RI	BYPASS MODE
0 ⁴	1	1	1	-	0	RI	BYPASS MODE

1. PAD INPUT REQUIRES HSTL LEVEL "HIGH" AND $V_{ddq} < V_{dd}$.

2. PAD INPUT REQUIRES HSTL LEVEL "LOW."

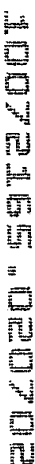
3. PAD INPUT REQUIRES CMOS LEVEL "HIGH" AND $V_{ddq} = V_{dd}$.

4. PAD INPUT REQUIRES CMOS LEVEL "LOW."

RECEIVER TRUTH TABLE

FIG. 7

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INPUTS						OUTPUTS	
RI	POR	EVAL	SENSE	XFER	CNTN0- CNTN5 CNTP0- CNTP5 PVTP0- PVTP5	ZPCNT DWN	ZNCNT DWN
0	X	X	X	X	X	0	0
X	0	X	X	X	X	0	0
1	1	1	1	1	X	X ¹	X ¹
1	1	1	0	1	X	1 ²	1 ³
1	1	1	0	1	X	0 ⁴	0 ⁵
1	1	1	0	0	X	LATCH ⁶	LATCH ⁶
1	1	0	0	0	X	HOLD ⁷	HOLD ⁷

1. EVAL = 1, POWER UP THE CELL; SENSE = 1, NULLS COMPARATOR INPUTS.
2. ZPCNTDWN = 1, WHEN VPADR > $V_{ddq}/2$
3. ZNCNTDWN = 1, WHEN VNEVAL < $V_{ddq}/2$
4. ZPCNTDWN = 0, WHEN VPADR < $V_{ddq}/2$
5. ZNCNTDWN = 0, WHEN VNEVAL > $V_{ddq}/2$
6. XFER = 0, LATCHES THE COMPARATOR OUTPUTS.
7. THE REFERENCE I/O IS POWERED DOWN AND THE PRESENT STATES OF THE OUTPUTS ARE HELD.

REF TRUTH TABLE

FIG. 9

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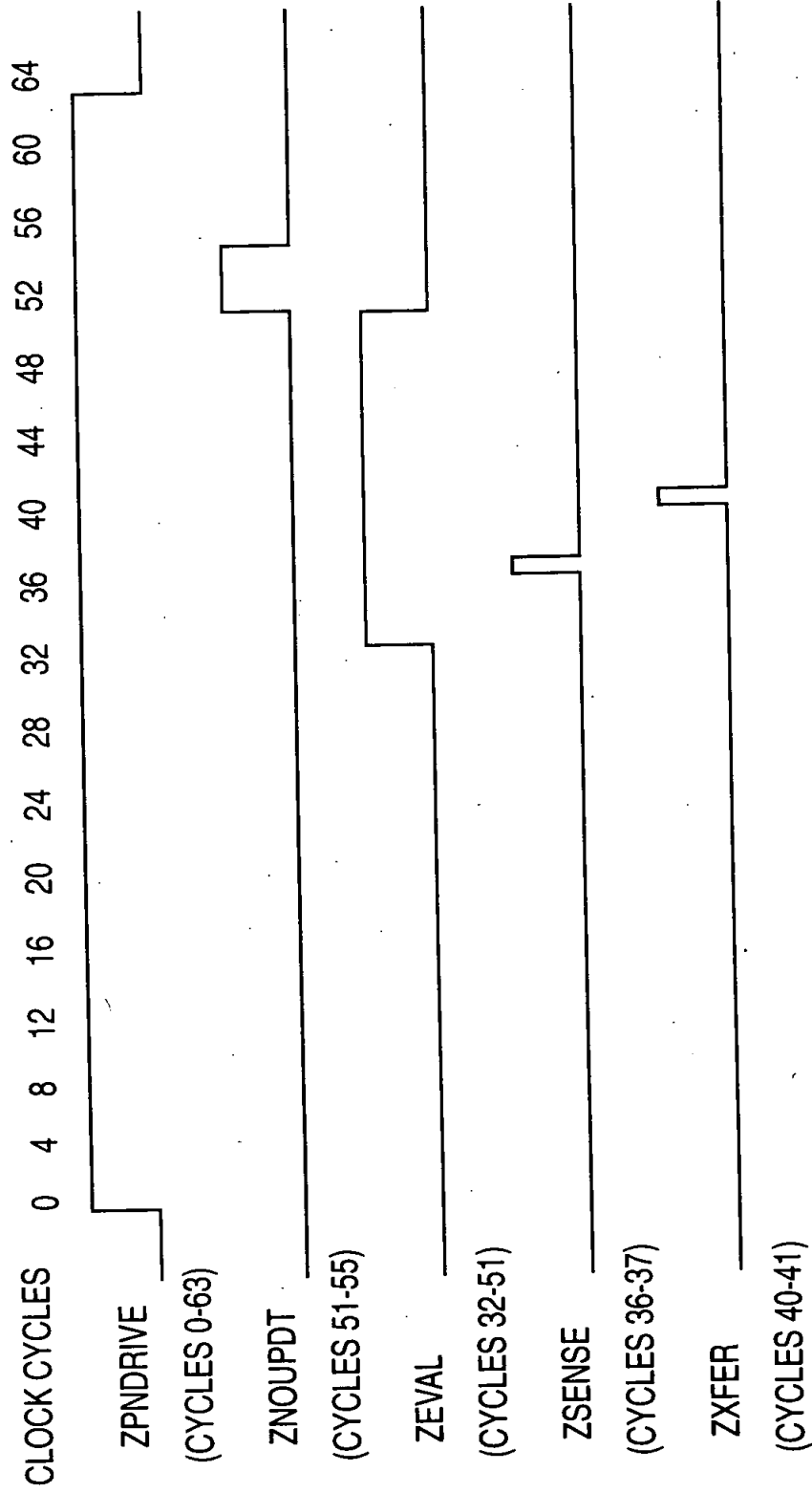


FIG. 10